

Explorations in low area overhead DfT techniques for sequential BIST

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Fast test cost calculation for hybrid BIST in digital systems

Orasson, Elmet; Raidma, Rein; **Ubar, Raimund-Johannes**; **Jervan, Gert**; Peng, Zebo Euromicro Symposium on Digital Systems Design : [Architectures, Methods and Tools : DSD 2001] : September 4-6, 2001, Warsaw, Poland : proceedings 2001 / p. 318-325 : ill <https://www.semanticscholar.org/paper/Fast-test-cost-calculation-for-hybrid-BIST-in-Orasson-Raidma/5aafcd5a18c2aabf0ad20cac10af10727f3c58f>

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Raidma, Rein A & A 2002 / 3, lk. 7-13 https://artiklid.elnet.ee/record=b1009960*est